High Speed CMOS Logic – 54HC86

Quadruple 2-Input Exclusive OR Gate IC in bare die form

Rev 1.0
21/11/17

Description

The 54HC86 is fabricated using a 2.5µm 5V CMOS process and has the same high speed performance of LSTTL combined with CMOS low power consumption. Device inputs are compatible with standard CMOS outputs and with LSTTL outputs with the use of pull-up resistors. Input and Output buffers enable low noise and stable outputs. Inputs are also protected against ESD and voltage transients. The device performs the Boolean functions $Y = A \oplus B = \overline{A}B + A\overline{B}$ in positive logic.

Features:

- Low Input Current: 1µA
- Output Drive Capability: 10 LSTTL loads
- Outputs directly interface CMOS, NMOS and TTL
- Operating Voltage Range: 2V to 6V
- CMOS High Noise Immunity
- Function compatible with 54LS86
- Full Military Temperature Range.

Ordering Information

The following part suffixes apply:

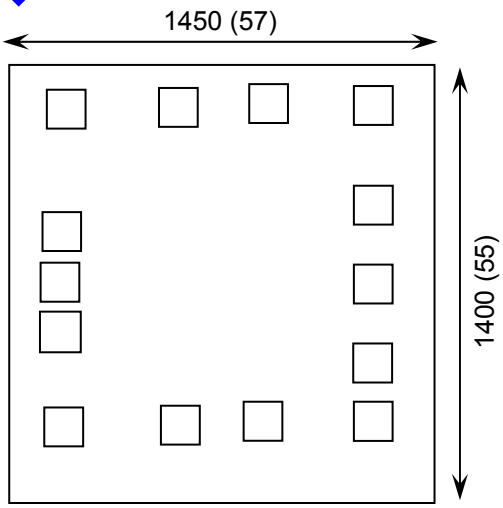
- No suffix - MIL-STD-883 /2010B Visual Inspection
- "**H**" - MIL-STD-883 /2010B Visual Inspection
  + MIL-PRF-38534 Class H LAT
- "**K**" - MIL-STD-883 /2010A Visual Inspection (Space)
  + MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

Die Dimensions in µm (mils)



Supply Formats:

- Default – Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape – On request
- Unsawn Wafer – On request
- Die Thickness <> 350µm(14 Mils) – On request
- Assembled into Ceramic Package – On request

Mechanical Specification

Die Size (Unsawn)	1450 x 1400 57 x 55	µm mils
Minimum Bond Pad Size	120 x 120 4.72 x 4.72	µm mils
Die Thickness	350 (±20) 13.78 (±0.79)	µm mils
Top Metal Composition	Al 1%Si 1.1µm	
Back Metal Composition	N/A – Bare Si	

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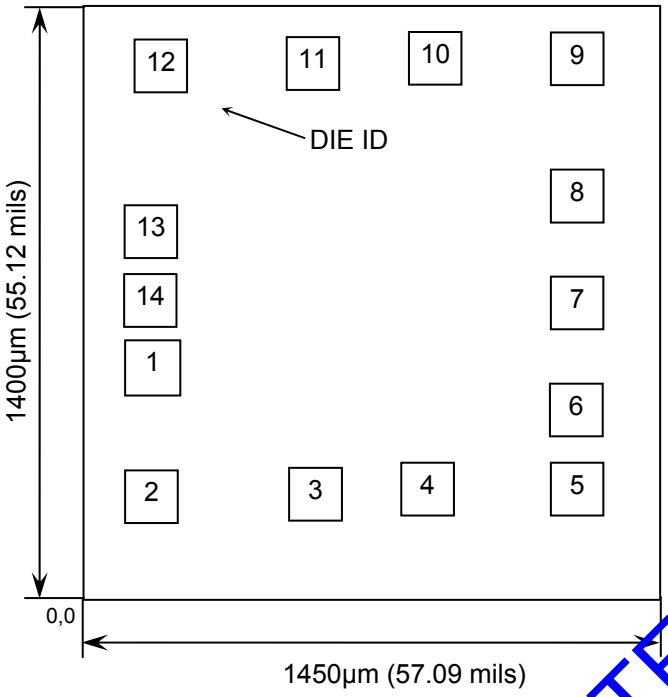
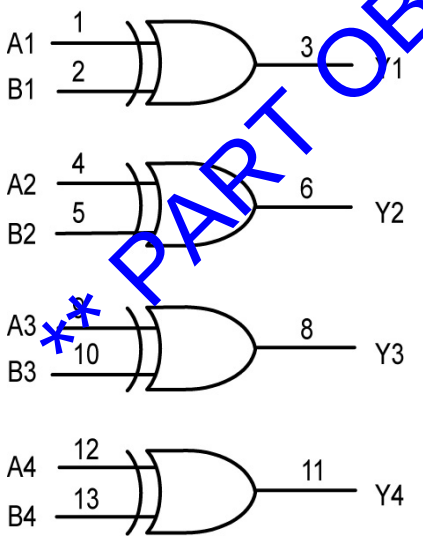
Pad Layout and Functions



PAD	FUNCTION	COORDINATES (mm)	
		X	Y
1	A1	0.115	0.495
2	B1	0.115	0.135
3	Y1	0.49	0.125
4	A2	0.78	0.125
5	B2	1.145	0.135
6	Y2	1.145	0.355
7	GND	1.145	0.665
8	Y3	1.145	0.975
9	A3	1.145	1.195
10	B3	0.780	1.205
11	Y4	0.490	1.205
12	A4	0.125	1.195
13	B4	0.115	1.835
14	V_{CC}	0.115	0.665
CONNECT CHIP BACK TO V_{CC} OR FLOAT			

Logic Diagram



$Y = A \oplus B$
$= \overline{A}B + A\overline{B}$

Pad 14 = V_{CC}
Pad 7 = GND

Function Table

INPUTS		OUTPUT
A	B	Y
L	L	L
L	H	H
H	L	H
H	H	L

H = High level (steady state)
L = Low level (steady state)

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Absolute Maximum Ratings[1]

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage (Referenced to GND)	V_{CC}	-0.5 to +7.0	V
DC Input Voltage (Referenced to GND)	V_{IN}	-0.5 to V_{CC} +0.5	V
DC Output Voltage (Referenced to GND)	V_{OUT}	-0.5 to V_{CC} +0.5	V
Clamp Diode Current	I_{IK}, I_{OK}	±20	mA
DC Output Current, per pad	I_{OUT}	±25	mA
DC V_{CC} or GND Current, per pad	I_{CC}	±50	mA
Power Dissipation in Still Air[2]	P_D	750	mW
Storage Temperature Range	T_{STG}	-65 to 150	°C

1. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, for extended periods, may reduce device reliability. **2.** Measured in plastic DIP package, results in die form are dependent on die attach and assembly method.

Recommended Operating Conditions[3] (Voltages referenced to GND)

PARAMETER		SYMBOL	MIN	MAX	UNITS
DC Supply Voltage		V_{CC}	2	6	V
DC Input or Output Voltage		V_{IN} ,V_{OUT}	0	V_{CC}	V
Operating Temperature Range		T_J	-55	+125	°C
Input Rise and Fall Times	V_{CC} = 2.0V	t_r, t_f	0	1000	ns
	V_{CC} = 4.5V		0	500	
	V_{CC} = 6.0V		0	400	

3. This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{IN} and V_{OUT} should be constrained to the range GND ≤ (V_{IN} or V_{OUT}) ≤ V_{CC}. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

DC Electrical Characteristics (Voltages Referenced to GND)

PARAMETER	SYMBOL	V_{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE[4]	
Minimum High-Level Input Voltage	V_{IH}	2.0V	V_{OUT} = 0.1V or V_{CC} -0.1V $\lvert I_{OUT} \rvert$ ≤ 20μA	1.5	1.5	1.5	V
		3.0V		2.1	2.1	2.1	
		4.5V		3.15	3.15	3.15	
		6.0V		4.2	4.2	4.2	
Maximum Low-Level Input Voltage	V_{IL}	2.0V	V_{OUT} = 0.1V or V_{CC} -0.1V $\lvert I_{OUT} \rvert$ ≤ 20μA	0.5	0.5	0.5	V
		3.0V		0.9	0.9	0.9	
		4.5V		1.35	1.35	1.35	
		6.0V		1.8	1.8	1.8	

4. −55°C ≤ T_J ≤ +125°C.

DC Electrical Characteristics Continued (Voltages referenced to GND)

PARAMETER	SYMBOL	V_{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE[3]	
Minimum High-Level Output Voltage	V_{OH}	2.0V	$V_{IN} = V_{IH}$ or V_{IL} $\lvert I_{OUT} \rvert \le 20\mu A$	1.9	1.9	1.9	V
		4.5V		4.4	4.4	4.4	
		6.0V		5.9	5.9	5.9	
		3.0V	$V_{IN} = V_{IH}$ $\lvert I_{OUT} \rvert \le 2.4mA$	2.48	2.34	2.20	V
		4.5V	$V_{IN} = V_{IH}$ or V_{IL} $\lvert I_{OUT} \rvert \le 4.0mA$	3.98	3.84	3.70	
		6.0V	$V_{IN} = V_{IH}$ or V_{IL} $\lvert I_{OUT} \rvert \le 5.2mA$	5.48	5.34	5.20	
Maximum Low-Level Output Voltage	V_{OL}	2.0V	$V_{IN} = V_{IL}$ or V_{IL} $\lvert I_{OUT} \rvert \le 20\mu A$	0.1	0.1	0.1	V
		4.5V		0.1	0.1	0.1	
		6.0V		0.1	0.1	0.1	
		3.0V	$V_{IN} = V_{IL}$ or V_{IL} $\lvert I_{OUT} \rvert \le 2.4mA$	0.26	0.33	0.40	V
		4.5V	$V_{IN} = V_{IL}$ or V_{IL} $\lvert I_{OUT} \rvert \le 4.0mA$	0.26	0.33	0.40	
		6.0V	$V_{IN} = V_{IL}$ or V_{IL} $\lvert I_{OUT} \rvert \le 5.2mA$	0.26	0.33	0.40	
Maximum Input Leakage Current	I_{IN}	6.0V	$V_{IN} = V_{CC}$ or GND	±0.1	±1.0	±1.0	µA
Maximum Quiescent Supply Leakage Current	I_{CC}	6.0V	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0\mu A$	1	10	40	µA

AC Electrical Characteristics[5]

PARAMETER	SYMBOL	V_{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE[4]	
Maximum Propagation Delay, Input A or B to Output Y (Figure 1,2)	t_{PLH}, t_{PHL}	2.0V	$C_L = 50pF$, $t_r = t_f = 6ns$	100	125	150	ns
		3.0V		80	90	110	
		4.5V		20	25	31	
		6.0V		17	21	26	
Maximum Output Rise and Fall Time, Any Output (Figure 1,2)	t_{TLH}, t_{THL}	2.0V	$C_L = 50pF$, $t_r = t_f = 6ns$	75	95	110	ns
		3.0V		30	40	55	
		4.5V		15	19	22	
		6.0V		13	16	19	

5. Not production tested in die form, characterized by chip design and tested in package.

AC Electrical Characteristics Continued[5]

PARAMETER	SYMBOL	V_{CC}	CONDITIONS	LIMITS			UNITS
				25°C	85°C	FULL RANGE[4]	
Maximum Input Capacitance	C_{IN}	-	-	10	10	10	pF
Power Dissipation Capacitance Per Gate[6]	C_{PD}	-	T_J = 25°C, V_{CC} =5.0V	TYPICAL			pF
				33			

5. Not production tested in die form, characterized by chip design and tested in package.
6. Used to determine the no-load dynamic power consumption: $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$.

Switching Waveforms

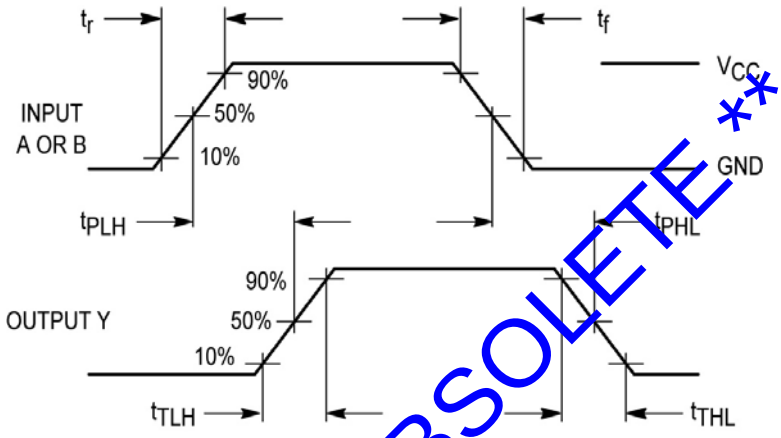
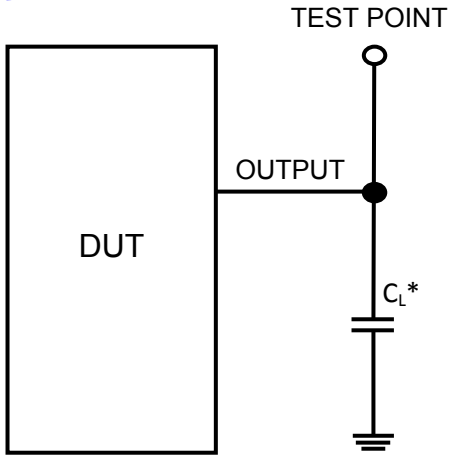


Figure 1 – Propagation Delay & Timing

Test Circuit



* Includes all probe and jig capacitance

Figure 2